

<b>Notice of References Cited</b>	Application/Control No. 10/723,840	Applicant(s)/Patent Under Reexamination GEYI WEN ET AL	
	Examiner Tan Ho	Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,486,837 B2	11-2002	Spiegel et al.	343/702
*	B	US-6,842,142 B2	01-2005	Takesako et al.	343/700MS
*	C	US-6,831,607 B2	12-2004	Hebron et al.	343/700MS
*	D	US-6,670,923 B1	12-2003	Kadambi et al.	343/700MS
*	E	US-6,650,298 B2	11-2003	Abbasi et al.	343/702
*	F	US-6,639,560 B1	10-2003	Kadambi et al.	343/700MS
*	G	US-6,333,716 B1	12-2001	Pontoppidan, Morten	343/702
*	H	US-6,133,880 A	10-2000	Grangeat et al.	343/700MS
*	I	US-6,049,314 A	04-2000	Munson et al.	343/846
*	J	US-5,929,813 A	07-1999	Eggleston, Steve W	343/700MS
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.